

High Current Transistors NPN Silicon

BC489, A, B

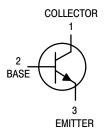
MAXIMUM RATINGS

Rating	Symbol	Value	Unit	
Collector–Emitter Voltage	VCEO	80	Vdc	
Collector–Base Voltage	VCBO	80	Vdc	
Emitter–Base Voltage	V _{EBO}	5.0	Vdc Adc	
Collector Current — Continuous	IC	0.5		
Total Device Dissipation @ T _A = 25°C Derate above 25°C	PD	625 5.0	mW mW/°C	
Total Device Dissipation @ T _C = 25°C Derate above 25°C			Watt mW/°C	
Operating and Storage Junction Temperature Range	T _J , T _{stg}	-55 to +150	°C	



THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	200	°C/W
Thermal Resistance, Junction to Case	$R_{\theta JC}$	83.3	°C/W



ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

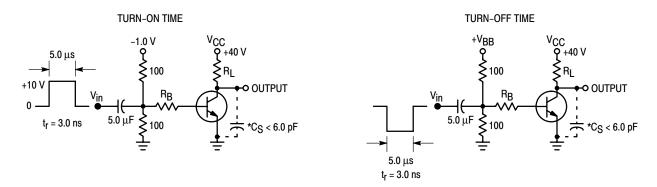
Symbol V(BR)CEO	Min	Тур	Max	Unit
V(BR)CFO				
V(BR)CEO				
(2.1)020	80	_	_	Vdc
V(BR)CBO	80	_	_	Vdc
V(BR)EBO	5.0	_	_	Vdc
ІСВО		_	100	nAdc
hFE	40 60 100 160	— — 160 260	 400 250 400	_
	V(BR)EBO	V(BR)EBO 5.0 ICBO — hFE 40 60 100	V(BR)EBO 5.0 — ICBO — — hFE 40 — 60 — 100 160 160 260	V(BR)EBO 5.0 — — — — — — — — — — — — — — — — — — —

^{1.} Pulse Test: Pulse Width = 300 μ s, Duty Cycle 2%.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted) (Continued)

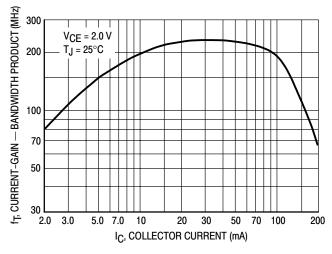
Characteristic	Symbol	Min	Тур	Max	Unit
ON CHARACTERISTICS* (Continued)					
Collector–Emitter Saturation Voltage (I _C = 500 mAdc, I _B = 50 mAdc) (I _C = 1.0 Adc, I _B = 100 mAdc)	VCE(sat)	_ _	0.2 0.3	0.5	Vdc
Base–Emitter Saturation Voltage (I _C = 500 mAdc, I _B = 50 mAdc) (I _C = 1.0 Adc, I _B = 100 mAdc)(1)	VBE(sat)	_	0.85 0.9	1.2	Vdc
DYNAMIC CHARACTERISTICS					
Current–Gain — Bandwidth Product (I _C = 50 mAdc, V _{CE} = 2.0 Vdc, f = 100 MHz)	f _T	_	200	_	MHz
Output Capacitance (V _{CB} = 10 Vdc, I _E = 0, f = 1.0 MHz)	C _{ob}	_	7.0	_	pF
Input Capacitance (VEB = 0.5 Vdc, IC = 0, f = 1.0 MHz)	C _{ib}	_	50	_	pF

^{1.} Pulse Test: Pulse Width = 300 μ s, Duty Cycle 2.0%.



*Total Shunt Capacitance of Test Jig and Connectors For PNP Test Circuits, Reverse All Voltage Polarities

Figure 1. Switching Time Test Circuits



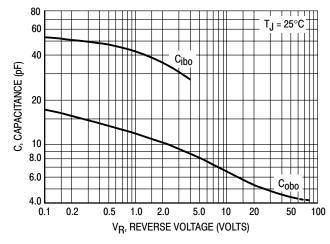


Figure 2. Current-Gain — Bandwidth Product

Figure 3. Capacitance

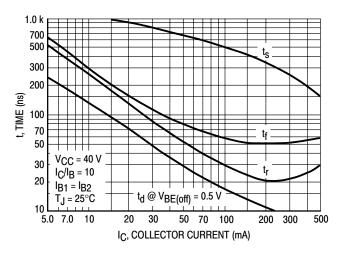


Figure 4. Switching Time

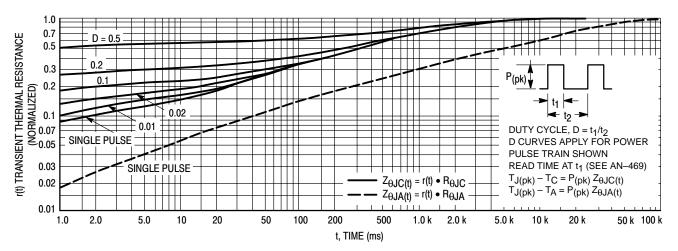


Figure 5. Thermal Response

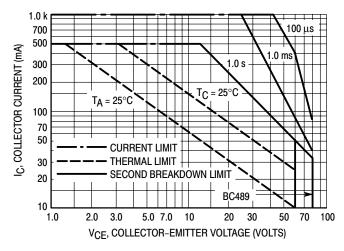


Figure 6. Active Region — Safe Operating Area

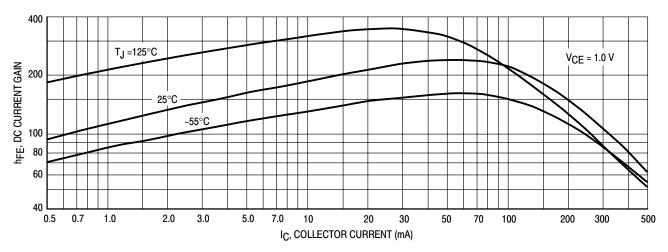


Figure 7. DC Current Gain

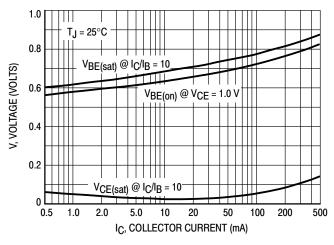


Figure 8. "On" Voltages

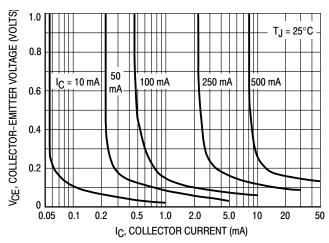


Figure 9. Collector Saturation Region

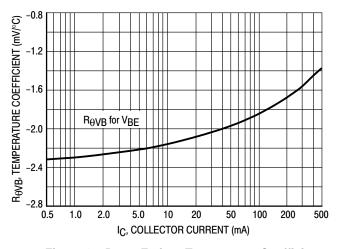


Figure 10. Base-Emitter Temperature Coefficient

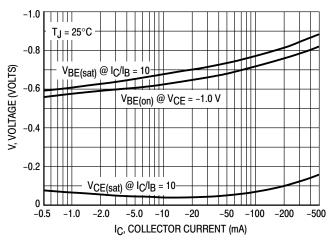


Figure 11. "On" Voltages

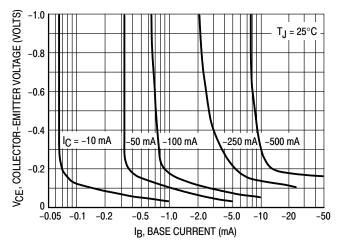


Figure 12. Collector Saturation Region

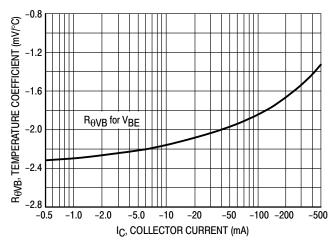
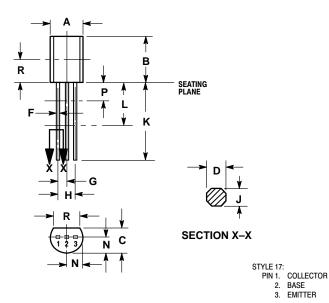


Figure 13. Base-Emitter Temperature Coefficient

PACKAGE DIMENSIONS

CASE 029-04 (TO-226AA) ISSUE AD



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
 3. CONTOUR OF PACKAGE BEYOND DIMENSION R IS UNCONTROLLED.
 4. DIMENSION F APPLIES BETWEEN P AND L. DIMENSIONS D AND J APPLY BETWEEN L AND K MIMIMUM. LEAD DIMENSION IS UNCONTROLLED IN P AND BEYOND DIMENSION K MINIMUM.

		INC	HES	MILLIN	IETERS
D	MIC	MIN	MAX	MIN	MAX
	Α	0.175	0.205	4.44	5.21
	В	0.290	0.310	7.37	7.87
	С	0.125	0.165	3.18	4.19
	D	0.018	0.021	0.457	0.533
	F	0.016	0.019	0.407	0.482
	G	0.045	0.055	1.15	1.39
	Н	0.095	0.105	2.42	2.66
	J	0.018	0.024	0.46	0.61
	K	0.500		12.70	
	L	0.250		6.35	
	N	0.080	0.105	2.04	2.66
	Р		0.100		2.54
	R	0.135		3.43	

Notes

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer.

PUBLICATION ORDERING INFORMATION

Literature Fulfillment

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada

Email: ONlit@hibbertco.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

JAPAN: ON Semiconductor, Japan Customer Focus Center 4–32–1 Nishi–Gotanda, Shinagawa–ku, Tokyo, Japan 141–0031

Phone: 81–3–5740–2700 Email: r14525@onsemi.com

ON Semiconductor Website: http://onsemi.com

For additional information, please contact your local

Sales Representative.